ABSTRACT OF THE DISCLOSURE

IMPROVED DIGITAL IMAGING CIRCUIT AND METHOD

An active pixel sensor (APS) circuit which provides enhanced test and signal processing capabilities. APSs usually include pixel cells arranged in an array of rows and columns. Selectably enableable coupling conductors are provided between principal conductors in the array to permit a signal on one principal conductors to propagate to another principal conductors. The principal conductors include row, reset and column conductors. Signal propagation for testing purposes and for normal mode operation are disclosed.

Figure 1